

FDD8880 N-Channel PowerTrench[®] MOSFET 30V, 58A, $9m\Omega$

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{\text{DS}(\text{ON})}$ and fast switching speed.

Applications

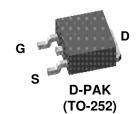
DC/DC converters



March 2015

Features

- $r_{DS(ON)} = 9m\Omega$, $V_{GS} = 10V$, $I_D = 35A$
- $r_{DS(ON)} = 12m\Omega$, $V_{GS} = 4.5V$, $I_D = 35A$
- High performance trench technology for extremely low ${\rm r}_{\rm DS(ON)}$
- · Low gate charge
- High power and current handling capability
- RoHS Compliant



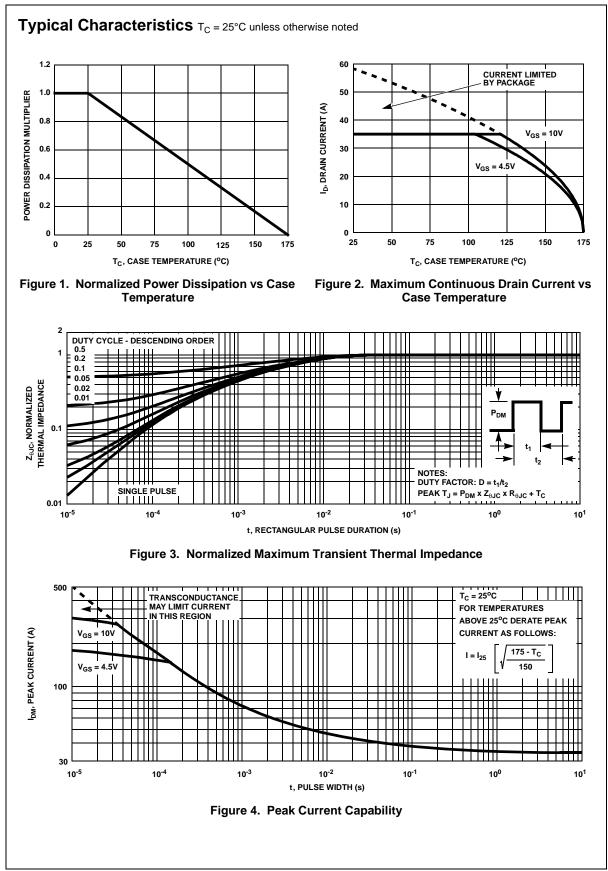


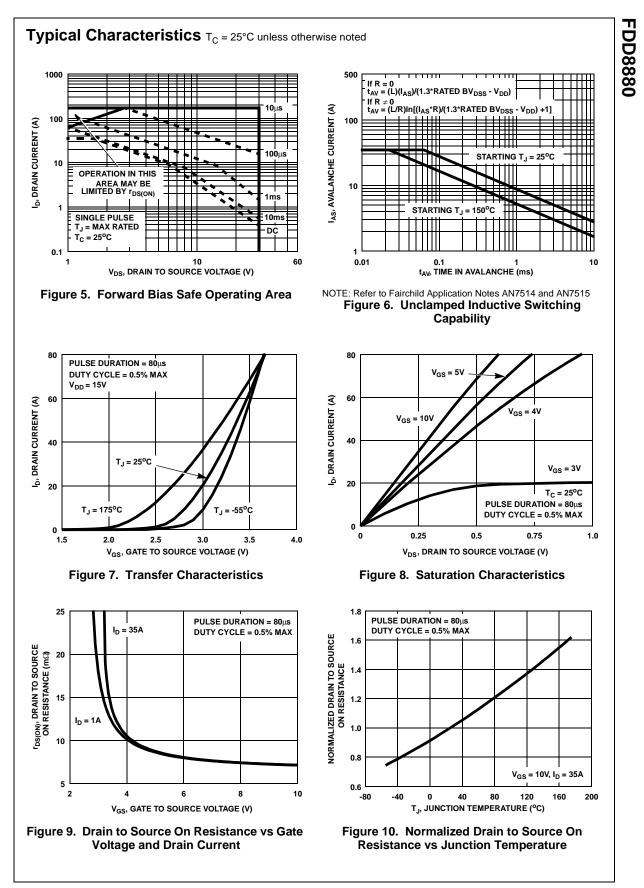
MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

Symbol		Par	Ratings	Units		
V _{DSS}	Drain to Sou	urce Voltage	30	V		
V _{GS}	Gate to Sou	rce Voltage	±20	V		
۱ _D	Drain Curre	nt				
	Continuous	$(T_{C} = 25^{\circ}C, V_{GS} = 10^{\circ}C)$	58	А		
	Continuous	$(T_{C} = 25^{\circ}C, V_{GS} = 4.3)$	51	A		
	Continuous	$(T_{amb} = 25^{\circ}C, V_{GS} =$	13	A		
	Pulsed		Figure 4	A		
E _{AS}	Single Pulse	e Avalanche Energy (I	53	mJ		
P _D	Power dissip	Power dissipation				W
	Derate abov	/e 25°C	0.37	W/ºC		
T _J , T _{STG}	Operating a	nd Storage Temperat	-55 to 175	°C		
						Ű
R _{θJC}		sistance Junction to (Case TO-252		2.73	°C/M
R _{θJC} R _{θJA}	Thermal Re Thermal Re	sistance Junction to C sistance Junction to A	Case TO-252 Ambient TO-252	² coppor pad area	2.73 100	°C/W
R _{θJC} R _{θJA} R _{θJA}	Thermal Re Thermal Re Thermal Re	sistance Junction to C sistance Junction to A sistance Junction to A	Case TO-252 Ambient TO-252 Ambient TO-252, 1in		2.73	°C/W
R _{θJC} R _{θJA} R _{θJA} Packag	Thermal Re Thermal Re Thermal Re	sistance Junction to C sistance Junction to A	Case TO-252 Ambient TO-252 Ambient TO-252, 1in		2.73 100	°C/W °C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units	
Off Chara	octeristics						
B _{VDSS}	Drain to Source Breakdown Voltage	I _D = 250μA, V _{GS} = 0V	30	-	-	V	
		$V_{DS} = 24V$	-	-	1	1	
I _{DSS}	Zero Gate Voltage Drain Current	$V_{GS} = 0V$ $T_C = 150^{\circ}C$	-	-	250	μA	
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$	-	-	±100	nA	
	cteristics				•		
V _{GS(TH)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.2	-	2.5	V	
*GS(TH)		$I_D = 35A, V_{GS} = 10V$	-	0.007	0.009	-	
		$I_D = 35A, V_{GS} = 4.5V$	-	0.009	0.000	2Ω	
r _{DS(ON)}	Drain to Source On Resistance	$I_D = 35A, V_{GS} = 10V,$					
		$T_{\rm J} = 175^{\circ}{\rm C}$	-	0.013	0.015		
Dynamic	Characteristics						
C _{ISS}	Input Capacitance		-	1260	-	pF	
C _{OSS}	Output Capacitance	$-V_{DS} = 15V, V_{GS} = 0V,$	-	260	-	pF	
C _{RSS}	Reverse Transfer Capacitance	f = 1MHz	-	150	-	pF	
R _G	Gate Resistance	V _{GS} = 0.5V, f = 1MHz	-	2.3	-	Ω	
Q _{g(TOT)}	Total Gate Charge at 10V	$V_{GS} = 0V$ to 10V	-	23	31	nC	
Q _{g(5)}	Total Gate Charge at 5V	$V_{GS} = 0V$ to 5V	-	13	17	nC	
Q _{g(TH)}	Threshold Gate Charge	$V_{DD} = 0V_{to 1V} V_{DD} = 15V$	-	1.3	1.7	nC	
Q _{gs}	Gate to Source Gate Charge	$I_{D} = 35A$ $I_{a} = 1.0mA$	-	3.8	-	nC	
Q _{gs2}	Gate Charge Threshold to Plateau		-	2.5	-	nC	
Q _{gd}	Gate to Drain "Miller" Charge		-	5.0	-	nC	
	g Characteristics (V _{GS} = 10V)						
t _{ON}	Turn-On Time		-	-	147	ns	
t _{d(ON)}	Turn-On Delay Time		-	8	-	ns	
t _r	Rise Time	V _{DD} = 15V, I _D = 35A	-	91	-	ns	
t _{d(OFF)}	Turn-Off Delay Time	$V_{GS} = 10V, R_{GS} = 10\Omega$	-	38	-	ns	
t _f	Fall Time		-	32	-	ns	
t _{OFF}	Turn-Off Time		-	-	108	ns	
Drain-So	urce Diode Characteristics				•		
V _{SD}	Source to Drain Diode Voltage	I _{SD} = 35A	-	-	1.25	V	
		I _{SD} = 15A	-	-	1.0	V	
t _{rr}	Reverse Recovery Time $I_{SD} = 35A, dI_{SD}/dt = 100A/\mu s$		-	-	27	ns	
Q _{RR}	Reverse Recovered Charge	I _{SD} = 35A, dI _{SD} /dt = 100A/µs	-	-	14	nC	

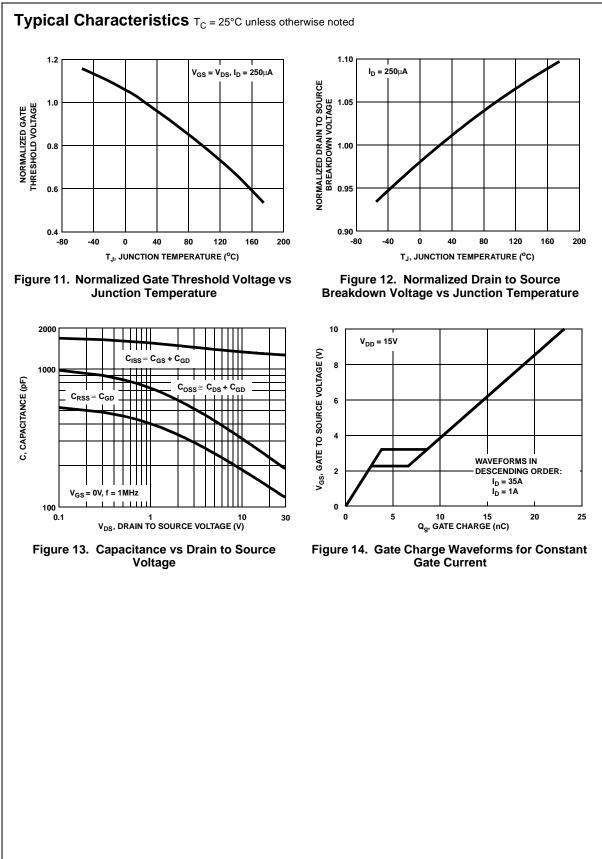






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Test Circuits and Waveforms

Figure 15. Unclamped Energy Test Circuit

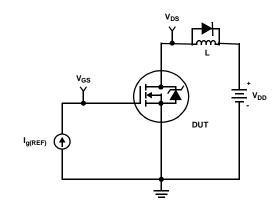


Figure 17. Gate Charge Test Circuit

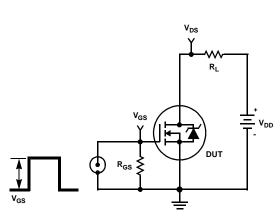
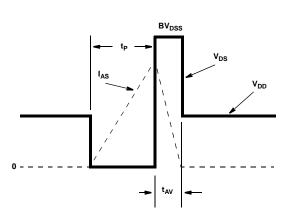
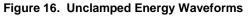


Figure 19. Switching Time Test Circuit





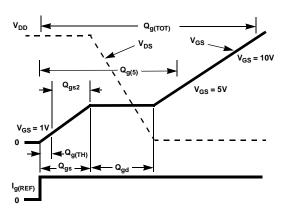
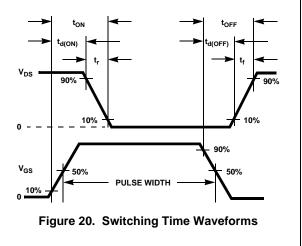


Figure 18. Gate Charge Waveforms



Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
(EQ. 1)

In using surface mount devices such as the TO-252 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- 1. Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- 6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta,JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

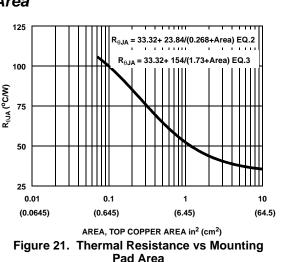
Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

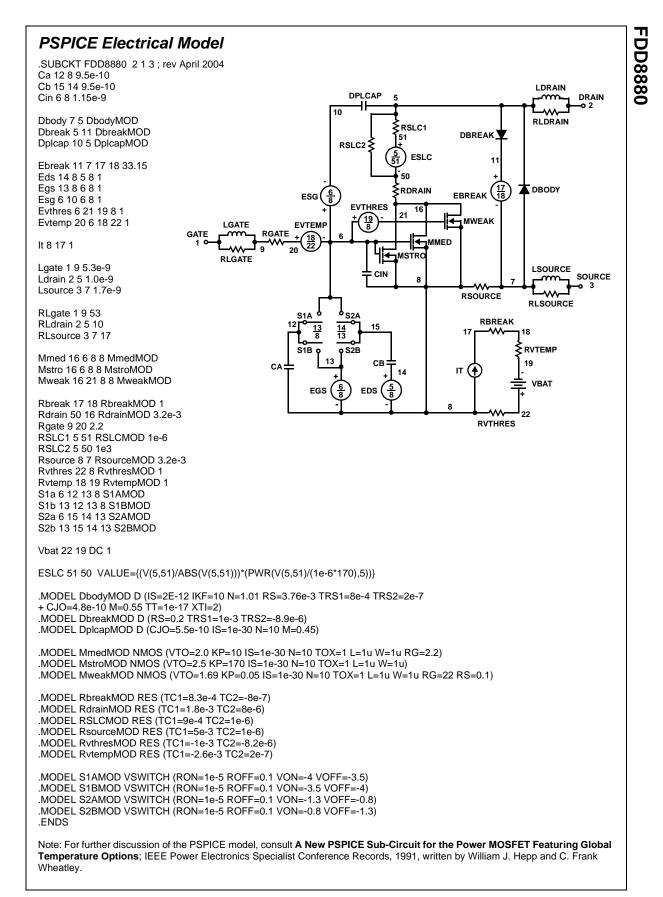
$$R_{\theta JA} = 33.32 + \frac{23.84}{(0.268 + Area)}$$
 (EQ. 2)

Area in Inches Squared

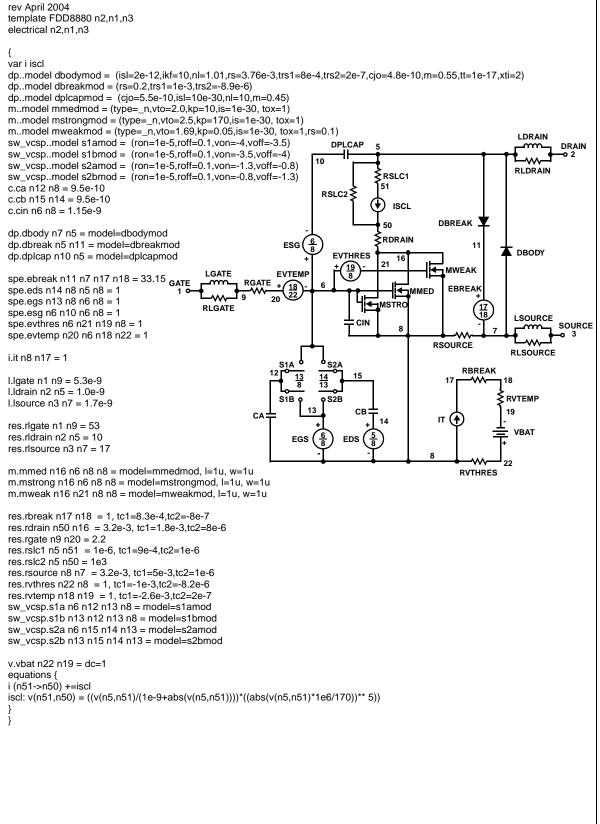
$$R_{\theta JA} = 33.32 + \frac{154}{(1.73 + Area)}$$
(EQ. 3)

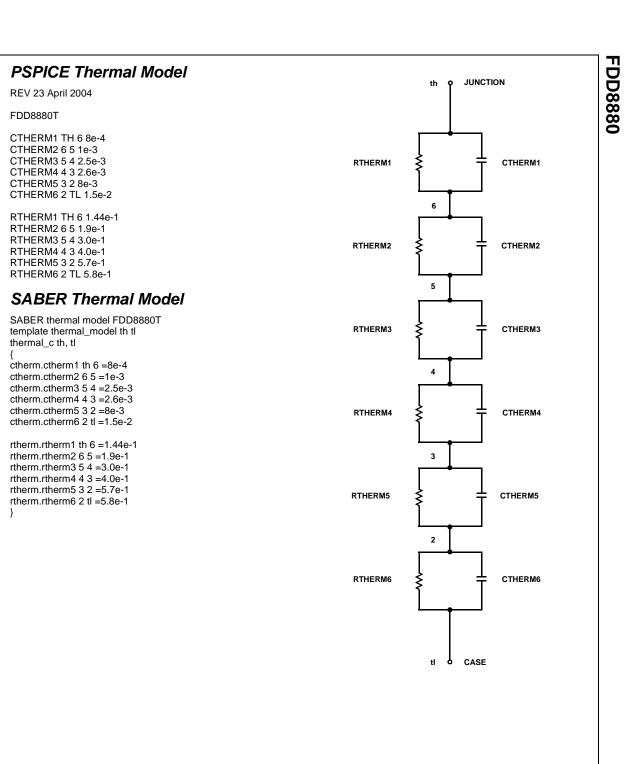
Area in Centimeters Squared





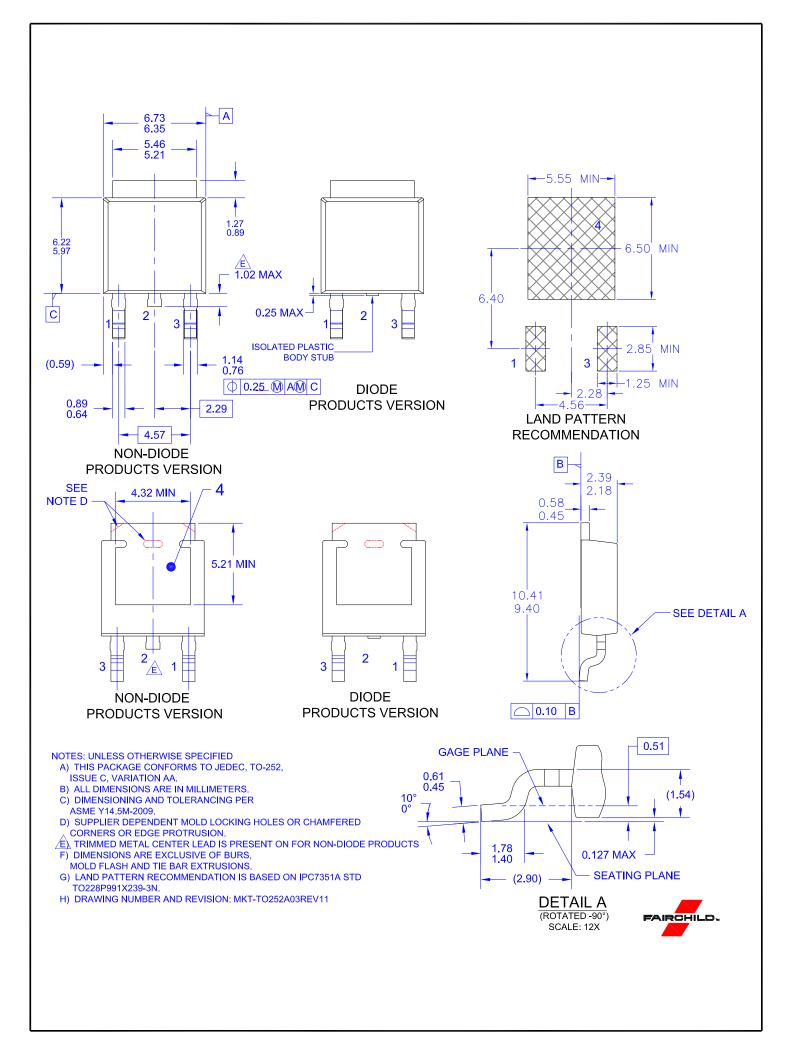
SABER Electrical Model

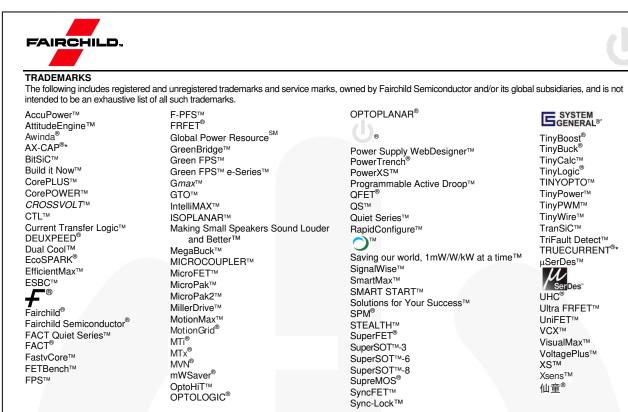




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